

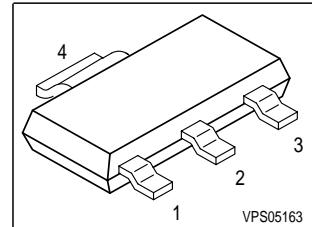
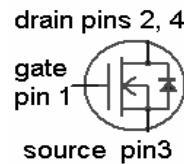
## SIPMOS® Small-Signal-Transistor

### Features

- N-Channel
- Enhancement mode
- Avalanche rated
- Logic Level
- dv/dt rated
- Pb-free lead plating; RoHS compliant
- Qualified according to AEC Q101
- Halogen-free according to IEC61249-2-21

### Product Summary

Drain source voltage	$V_{DS}$	60	V
Drain-Source on-state resistance	$R_{DS(on)}$	0.09	$\Omega$
Continuous drain current	$I_D$	2.6	A



Halogen-Free



RoHS

Type	Package	Tape and Reel	Marking	Packaging
BSP318S	PG-SOT223	H6327: 1000 pcs/r	BSP318S	Non dry

**Maximum Ratings**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current	$I_D$	2.6	A
Pulsed drain current $T_A = 25^\circ\text{C}$	$I_D$ puls	10.4	
Avalanche energy, single pulse $I_D = 2.6 \text{ A}, V_{DD} = 25 \text{ V}, R_{GS} = 25 \Omega$	$E_{AS}$	60	mJ
Avalanche current, periodic limited by $T_{jmax}$	$I_{AR}$	2.6	A
Avalanche energy, periodic limited by $T_{jmax}$	$E_{AR}$	0.18	mJ
Reverse diode dv/dt $I_S = 2.6 \text{ A}, V_{DS} = 20 \text{ V}, di/dt = 200 \text{ A}/\mu\text{s}, T_{jmax} = 150^\circ\text{C}$	dv/dt	6	kV/ $\mu\text{s}$
Gate source voltage	$V_{GS}$	$\pm 20$	V
Power dissipation $T_A = 25^\circ\text{C}$	$P_{tot}$	1.8	W
Operating and storage temperature	$T_j, T_{stg}$	-55... +150	°C
IEC climatic category; DIN IEC 68-1		55/150/56	
ESD Class JESD22-A114-HBM		Class 1b	

**Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Characteristics</b>					
Thermal resistance, junction - soldering point (Pin 4)	$R_{thJS}$	-	17	-	K/W
SMD version, device on PCB: @ min. footprint @ 6 cm <sup>2</sup> cooling area <sup>1)</sup>	$R_{thJA}$	-	100	-	
		-	-	70	

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Static Characteristics</b>					
Drain- source breakdown voltage $V_{GS} = 0 \text{ V}$ , $I_D = 0.25 \text{ mA}$	$V_{(\text{BR})DSS}$	60	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 20 \mu\text{A}$	$V_{GS(\text{th})}$	1.2	1.6	2	
Zero gate voltage drain current $V_{DS} = 60 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_j = 25^\circ\text{C}$ $V_{DS} = 60 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_j = 150^\circ\text{C}$	$I_{DSS}$	-	0.1	1	$\mu\text{A}$
-		-	-	100	
Gate-source leakage current $V_{GS} = 20 \text{ V}$ , $V_{DS} = 0 \text{ V}$	$I_{GSS}$	-	10	100	nA
Drain-Source on-state resistance $V_{GS} = 4.5 \text{ V}$ , $I_D = 2.6 \text{ A}$	$R_{DS(\text{on})}$	-	0.12	0.15	$\Omega$
Drain-Source on-state resistance $V_{GS} = 10 \text{ V}$ , $I_D = 2.6 \text{ A}$	$R_{DS(\text{on})}$	-	0.07	0.09	

<sup>1</sup>Device on 50mm\*50mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70  $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical without blown air.

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Dynamic Characteristics</b>					
Transconductance $V_{DS} \geq 2^* I_D * R_{DS(on)max}$ , $I_D = 2.6 \text{ A}$	$g_{fs}$	2.4	5.5	-	S
Input capacitance $V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$	$C_{iss}$	-	300	380	pF
Output capacitance $V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$	$C_{oss}$	-	90	120	
Reverse transfer capacitance $V_{GS} = 0 \text{ V}$ , $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$	$C_{rss}$	-	50	65	
Turn-on delay time $V_{DD} = 30 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 2.6 \text{ A}$ , $R_G = 16 \Omega$	$t_{d(on)}$	-	12	20	ns
Rise time $V_{DD} = 30 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 2.6 \text{ A}$ , $R_G = 16 \Omega$	$t_r$	-	15	25	
Turn-off delay time $V_{DD} = 30 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 2.6 \text{ A}$ , $R_G = 16 \Omega$	$t_{d(off)}$	-	20	30	
Fall time $V_{DD} = 30 \text{ V}$ , $V_{GS} = 4.5 \text{ V}$ , $I_D = 2.6 \text{ A}$ , $R_G = 16 \Omega$	$t_f$	-	15	25	

**Electrical Characteristics, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified**

<b>Parameter</b>	<b>Symbol</b>	<b>Values</b>			<b>Unit</b>
		<b>min.</b>	<b>typ.</b>	<b>max.</b>	

**Dynamic Characteristics**

Gate charge at threshold $V_{DD} = 40 \text{ V}, I_D = 0.1 \text{ A}, V = 1 \text{ V}$	$Q_{G(\text{th})}$	-	0.4	0.6	nC
Gate charge at $V_{GS} = 5 \text{ V}$ $V_{DD} = 40 \text{ V}, I_D = 2.6 \text{ A}, V_{GS} = 0 \text{ to } 5 \text{ V}$	$Q_g(5)$	-	7	10	
Gate charge total $V_{DD} = 40 \text{ V}, I_D = 2.6 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$	$Q_g$	-	14	20	
Gate plateau voltage $V_{DD} = 40 \text{ V}, I_D = 2.6 \text{ A}$	$V_{(\text{plateau})}$	-	3.6	-	V

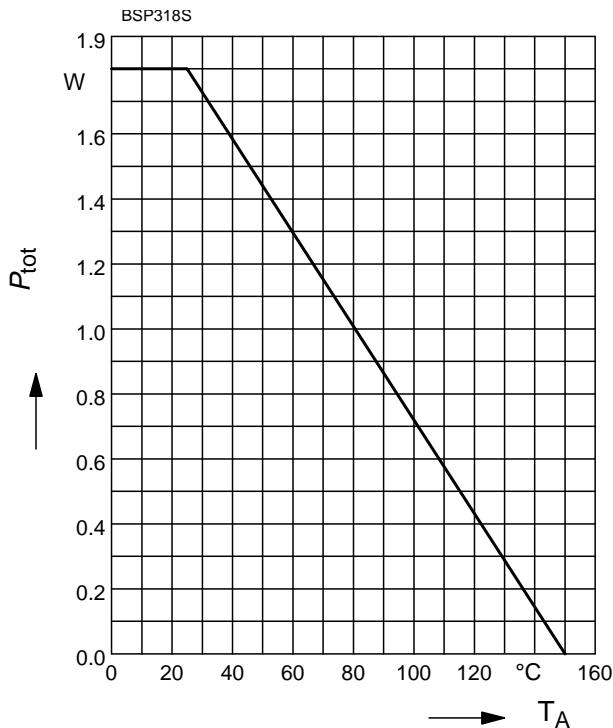
<b>Parameter</b>	<b>Symbol</b>	<b>Values</b>			<b>Unit</b>
		<b>min.</b>	<b>typ.</b>	<b>max.</b>	

**Reverse Diode**

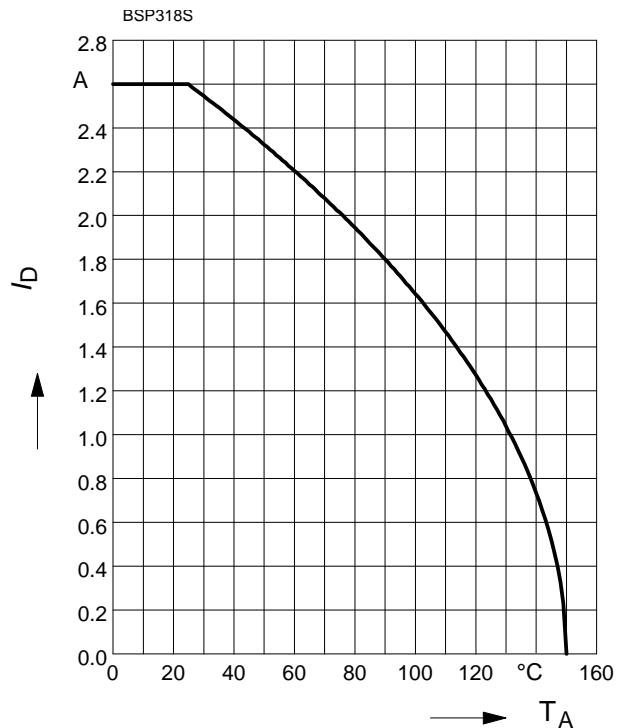
Inverse diode continuous forward current $T_A = 25^\circ\text{C}$	$I_S$	-	-	2.6	A
Inverse diode direct current,pulsed $T_A = 25^\circ\text{C}$	$I_{SM}$	-	-	10.4	
Inverse diode forward voltage $V_{GS} = 0 \text{ V}, I_F = 5.2 \text{ A}$	$V_{SD}$	-	0.95	1.2	V
Reverse recovery time $V_R = 30 \text{ V}, I_F = I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	$t_{rr}$	-	50	75	ns
Reverse recovery charge $V_R = 30 \text{ V}, I_F = I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	$Q_{rr}$	-	0.1	0.15	$\mu\text{C}$

**Power Dissipation**

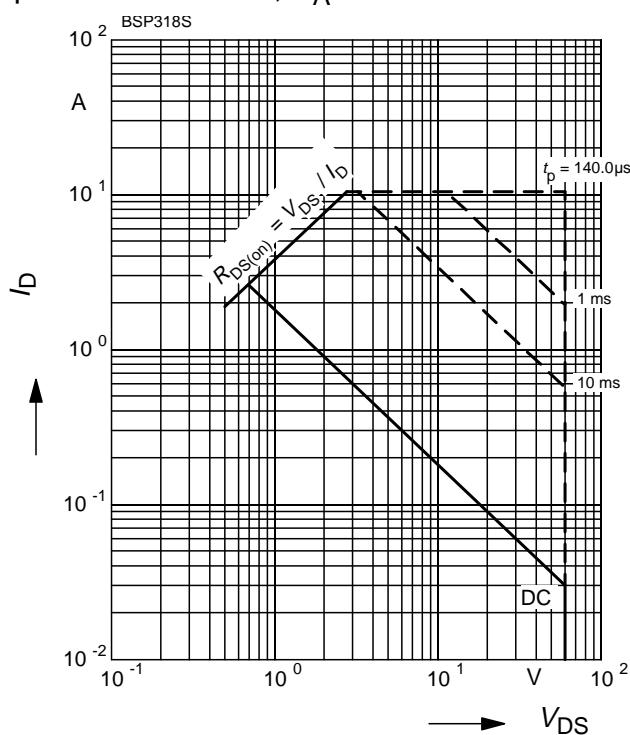
$$P_{\text{tot}} = f(T_A)$$


**Drain current**

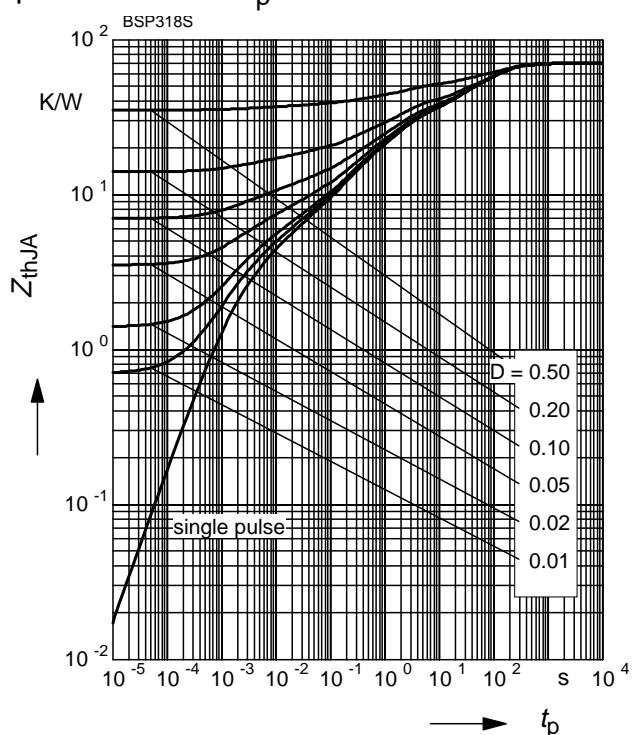
$$I_D = f(T_A)$$


**Safe operating area**

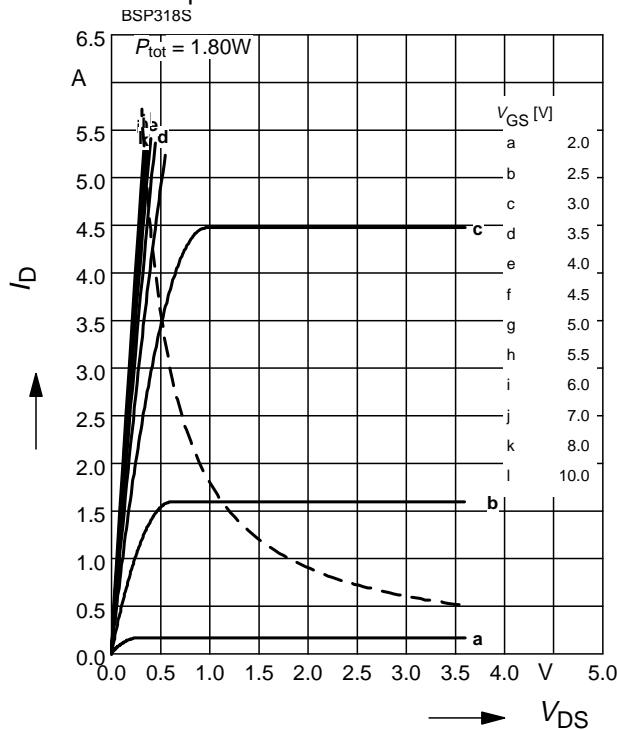
$$I_D = f(V_{DS})$$

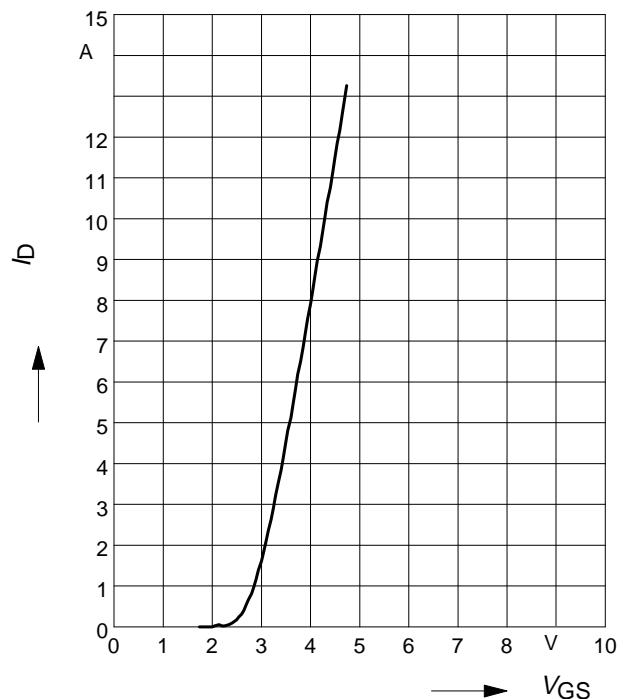
 parameter :  $D = 0$ ,  $T_A = 25^\circ\text{C}$ 

**Transient thermal impedance**

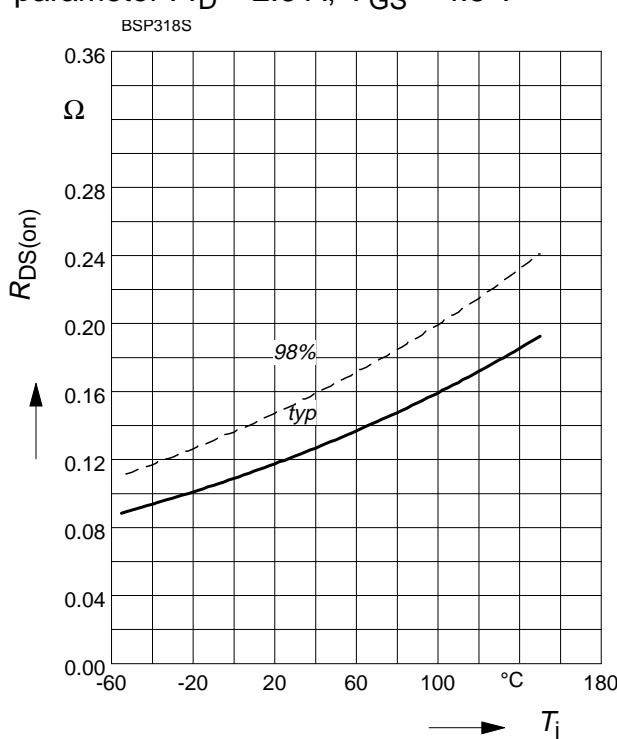
$$Z_{\text{thJA}} = f(t_p)$$

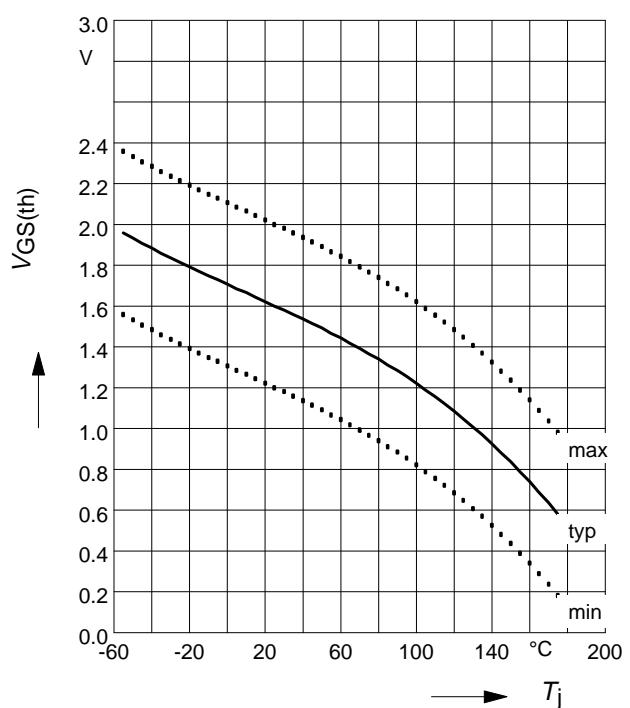
 parameter :  $D = t_p/T$ 


**Typ. output characteristic**
 $I_D = f(V_{DS})$ ;  $T_j = 25^\circ\text{C}$ 

 parameter:  $t_p = 80 \mu\text{s}$ 

**Typ. transfer characteristics  $I_D = f(V_{GS})$** 
 $V_{DS} \geq 2 \times I_D \times R_{DS(\text{on})\text{max}}$ 

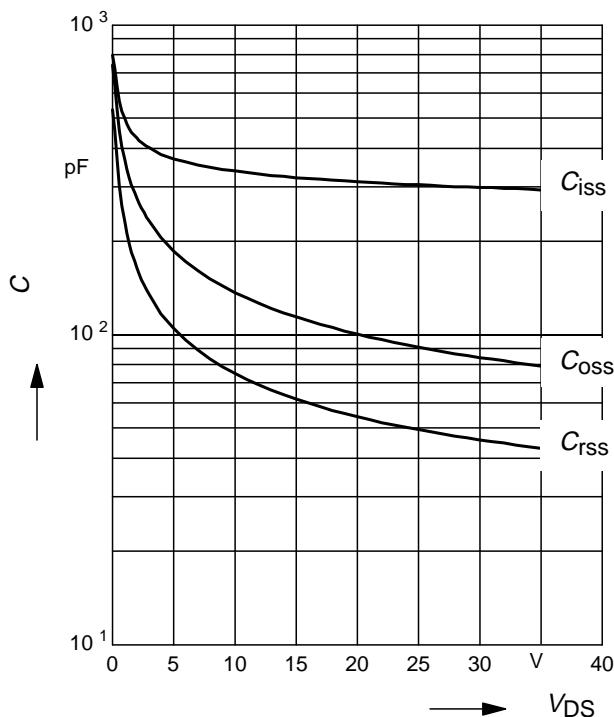
 parameter:  $t_p = 80 \mu\text{s}$ 

**Drain-source on-resistance**
 $R_{DS(\text{on})} = f(T_j)$ 

 parameter:  $I_D = 2.6 \text{ A}$ ,  $V_{GS} = 4.5 \text{ V}$ 

**Gate threshold voltage**
 $V_{GS(\text{th})} = f(T_j)$ 

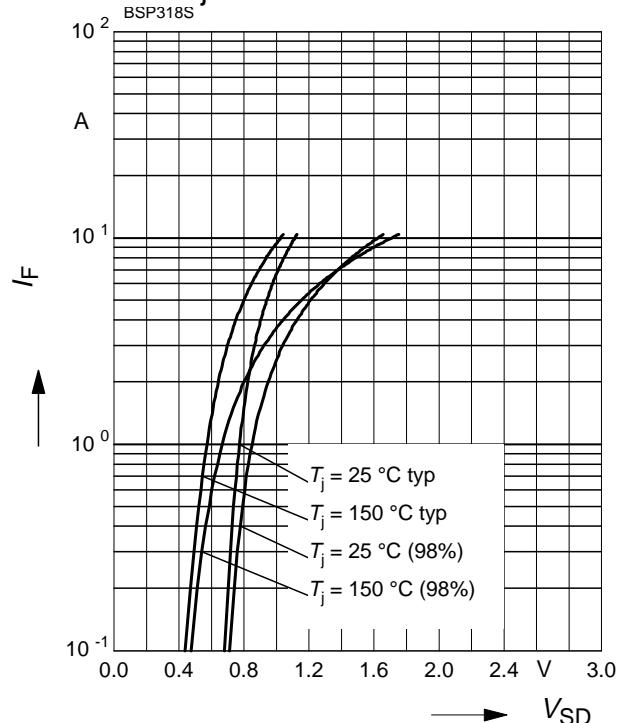
 parameter:  $V_{GS} = V_{DS}$ ,  $I_D = 20 \mu\text{A}$ 


**Typ. capacitances**

$$C = f(V_{DS})$$

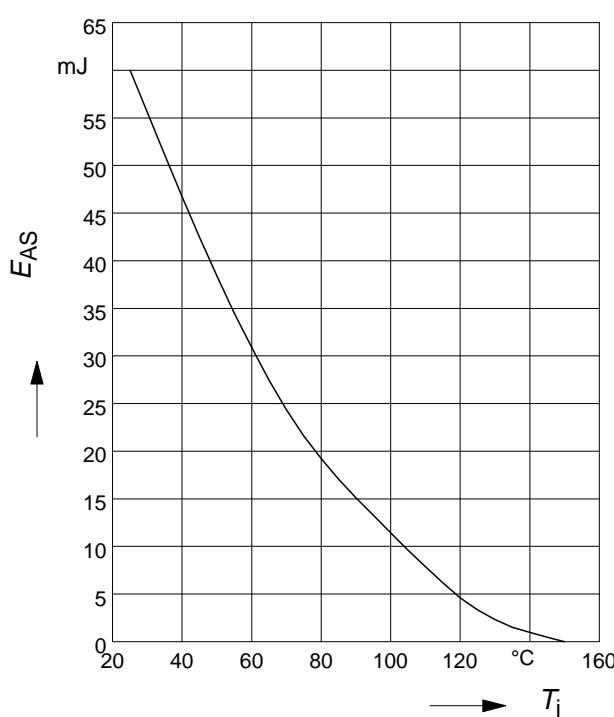
 parameter:  $V_{GS}=0$  V,  $f=1$  MHz

**Forward characteristics of reverse diode**

$$I_F = f(V_{SD})$$

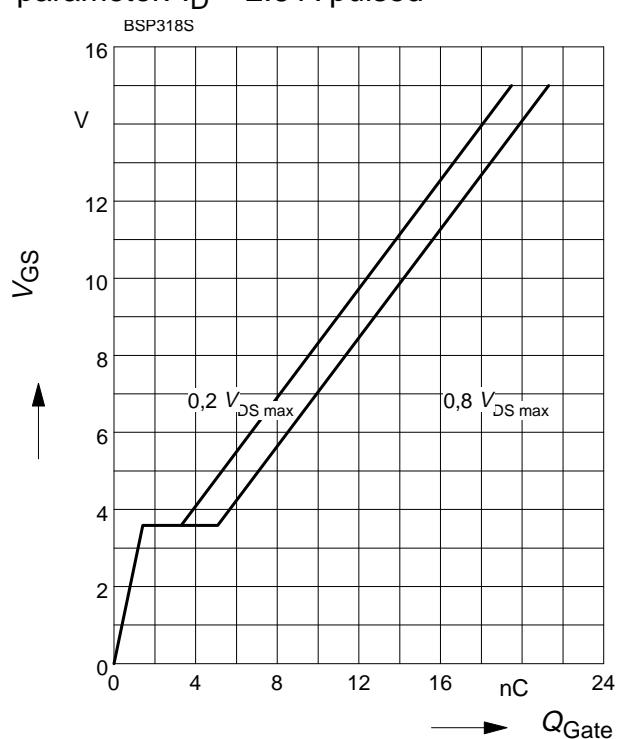
 parameter:  $T_j$ ,  $t_p = 80 \mu\text{s}$ 

**Avalanche Energy**  $E_{AS} = f(T_j)$ 

 parameter:  $I_D = 2.6$  A,  $V_{DD} = 25$  V

$$R_{GS} = 25 \Omega$$

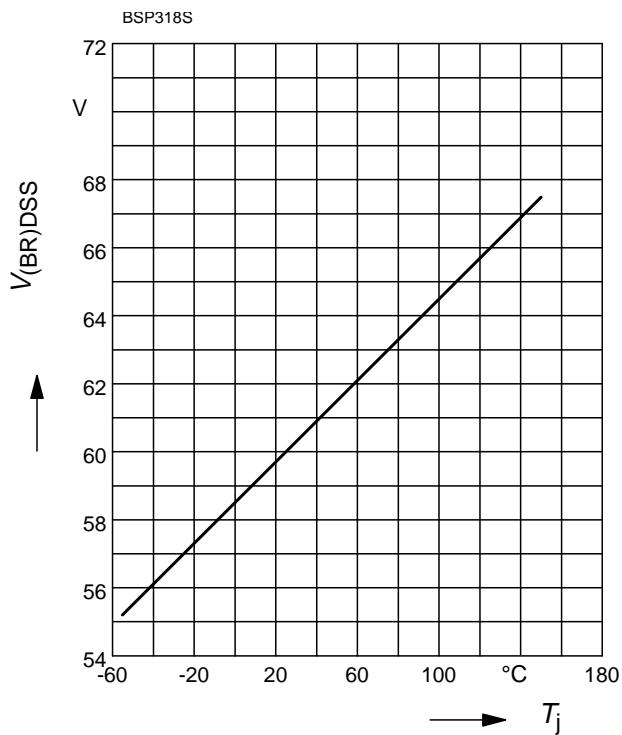

**Typ. gate charge**

$$V_{GS} = f(Q_{Gate})$$

 parameter:  $I_D = 2.6$  A pulsed


**Drain-source breakdown voltage**

$$V_{(BR)DSS} = f(T_j)$$



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